

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE **RECEIVED**
CENTRAL FAX CENTER

Serial No.: 10/707,388**Conf. No.:** 1387**OCT 14 2005****Filing Date:** 12/10/2003**Art Unit:** 2891**Applicant:** Divakaruni et al.**Examiner:** Fulk, Steven J.**Title:** SILICIDE RESISTOR IN BEOL
LAYER OF SEMICONDUCTOR
DEVICE AND METHOD**Docket No.:** FIS920030274US1
(IBMF-0032)**COMMISSIONER FOR PATENTS****DESTINATION FACSIMILE NUMBER:** 571-273-8300

Transmitted herewith is:

Request for Reconsideration in 8 pages

in the above identified application.

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CENTRAL FAX CENTER**OCT 14 2005****IN THE UNITED STATES PATENT AND TRADEMARK OFFICE****In Re Application of:** Divakaruni et al.**Conf. No.:** 1387**Serial No.:** 10/707,388**Art Unit:** 2891**Filed:** 12/10/2003**Dkt. #:** FIS920030274US1 (IBMF-0032)**Title:** SILICIDE RESISTOR IN BEOL
LAYER OF SEMICONDUCTOR
DEVICE AND METHOD**Examiner:** Fulk, Steven J.Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450**REQUEST FOR RECONSIDERATION**

Sir:

I. INTRODUCTORY COMMENTS:

In response to the Office Action of July 28, 2005, please reconsider the above-referenced patent application in view of the following remarks: